• • •	Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/689,727	FURUKAWA ET AL.
Examiner	Art Unit
Kiet Doan	2683

	SEARCHED				
Class	Subclass	Date	Examiner		
455	456.1, 132	8/16/2005	KD		
	446, 403		KD		
	513		KD		
	456.2		KD		
370	345		KD		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
@ad<"20021023" and cell\$1 same base near2 station and candidate near2 location	8/17/2005	KD
@ad<"20021023" and base near2 station same traffic same ratio same exceed\$1		KD
@ad<"20021023" and base near2 station same layout same calculat\$3		KD